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Agilent Technologies

HP 4286A RF LCR Meter

Technical Specifications

Specifications

Specifications describe the instrument's warranted performance over the temperature range of 0°C to 55°C (except as noted). Supplemental characteristics are intended to provide information that is useful in applying the instrument by giving non-warranted performance parameters. These are denoted as *typical*, *typically*, *nominal* or *approximate*. Warm up time must be greater than or equal to 30 minutes after power on for all specifications.

Specifications of the stimulus characteristics and measurement accuracy are defined at the tip of APC-7® connector of 3.5mm-7mm adapter connected to the test head.

Test Signal

Frequency Characteristics

Operating Frequency	1 MHz to 1000 MHz
A maximum of 10 frequencies can be programmed. An averaging factor can be set at each frequency point.	
Frequency Resolution	10 kHz
Frequency Accuracy	< ±10 ppm @23±5°C

Source Characteristics

Definition of OSC level

- Voltage level : $2 \times$ voltage level across the 50 Ω which is connected to the output terminal. (this level is approximately equal to the level when a terminal is open)
- Current level : $2 \times$ current level through the 50 Ω which is connected to the output terminal. (this level is approximately equal to the level when a terminal is shorted)
- Power level : when terminating with 50 Ω .

OSC Level

Voltage Range	10 mV _{rms} to 1 V _{rms}
Current Range	200 μ A to 20 mA
Power Range	-33 dBm to +7 dBm

OSC Level Resolution

Voltage Resolution

@ 0.22 V < V _{osc} ≤ 1 V	2 mV
@ 70 mV < V _{osc} ≤ 220 mV	0.5 mV
@ 22 mV < V _{osc} ≤ 70 mV	0.2 mV
@ 10 mV ≤ V _{osc} ≤ 22 mV	0.05 mV

Current Resolution

@ 4.4 mA < I _{osc} ≤ 20 mA	40 μA
@ 1.4 mA < I _{osc} ≤ 4.4 mA	10 μA
@ 0.44 mA < I _{osc} ≤ 1.4 mA	4 μA
@ 200 μA ≤ I _{osc} ≤ 440 μA	1 μA

Power Resolution 0.1 dBm

OSC Level Accuracy

Table 1. OSC Level Accuracy at Cable Length = 3 m, 23±5°C

Test Signal Voltage	Frequency Range	OSC Level Accuracy
0.5 V < V _{osc} ≤ 1 V	1 MHz ≤ frequency ≤ 500 MHz	±2 dB
	500 MHz < f ≤ 1000 MHz	+3 dB/-10 dB ¹
0.25 V ≤ V _{osc} ≤ 0.5 V	1 MHz ≤ frequency ≤ 1000 MHz	±2 dB
0.01 V ≤ V _{osc} < 0.25 V	1 MHz ≤ frequency ≤ 1000 MHz	±3 dB

¹ Typical data at temperature range is 5 through +40°C

Table 2. OSC Level Accuracy at Cable Length = 3 m, 0°C to +55°

Test Signal Voltage	Frequency Range	OSC Level Accuracy	
		5°C to 40°C	0°C to 55°C
0.5 V < V _{osc} ≤ 1 V	1 MHz ≤ frequency ≤ 500 MHz	±4 dB	±6 dB
	500 MHz < frequency ≤ 1000 MHz	+3 dB/-10 dB ¹	+5 dB/-12 dB ¹
0.25 V ≤ V _{osc} ≤ 0.5 V	1 MHz ≤ frequency ≤ 1000 MHz	±4 dB	±6 dB
0.01 V ≤ V _{osc} < 0.25 V	1 MHz ≤ frequency ≤ 1000 MHz	±5 dB	±7 dB

¹ Typical value

Table 3. OSC Level Accuracy at Cable Length = 1 m, 23±5°C

Test Signal Voltage	Frequency Range	OSC Level Accuracy
0.5 V < V _{osc} ≤ 1 V	1 MHz ≤ frequency ≤ 1000 MHz	±2 dB
0.25 V ≤ V _{osc} ≤ 0.5 V	1 MHz ≤ frequency ≤ 1000 MHz	±2 dB
0.01 V ≤ V _{osc} < 0.25 V	1 MHz ≤ frequency ≤ 1000 MHz	±3 dB

Table 4. OSC Level Accuracy at Cable Length = 1 m, 0°C to +55°

Test Signal Voltage	Frequency Range	OSC Level Accuracy	
		5°C to 40°C	0°C to 55°C
$0.5 \text{ V} < V_{\text{osc}} \leq 1 \text{ V}$	$1 \text{ MHz} \leq \text{frequency} \leq 1000 \text{ MHz}$	±4 dB	±6 dB
$0.25 \text{ V} \leq V_{\text{osc}} \leq 0.5 \text{ V}$	$1 \text{ MHz} \leq \text{frequency} \leq 1000 \text{ MHz}$	±4 dB	±6 dB
$0.01 \text{ V} \leq V_{\text{osc}} < 0.25 \text{ V}$	$1 \text{ MHz} \leq \text{frequency} \leq 1000 \text{ MHz}$	±5 dB	±7 dB

Typical OSC Level Accuracy 2 times of specification value
Connector APC-3.5®
Output Impedance 50 Ω (Nominal Value)
Level Monitor

Monitor Parameters OSC level (voltage, current)

Monitor Accuracy

Voltage $20 \log (1 + Y_0 \cdot 50 + Z_s / Z_x + E_a (\%) / 100)$ [dB] (Typical)
 Current $20 \log (1 + Y_0 \cdot Z_x + Z_s / 50 + E_a (\%) / 100)$ [dB] (Typical)

Where,

E_a : depends on measurement frequency and connector type. See measurement accuracy.

Z_s and Y₀ : depend on number of point averaging and OSC level. See measurement accuracy

Z_x : Measurement impedance

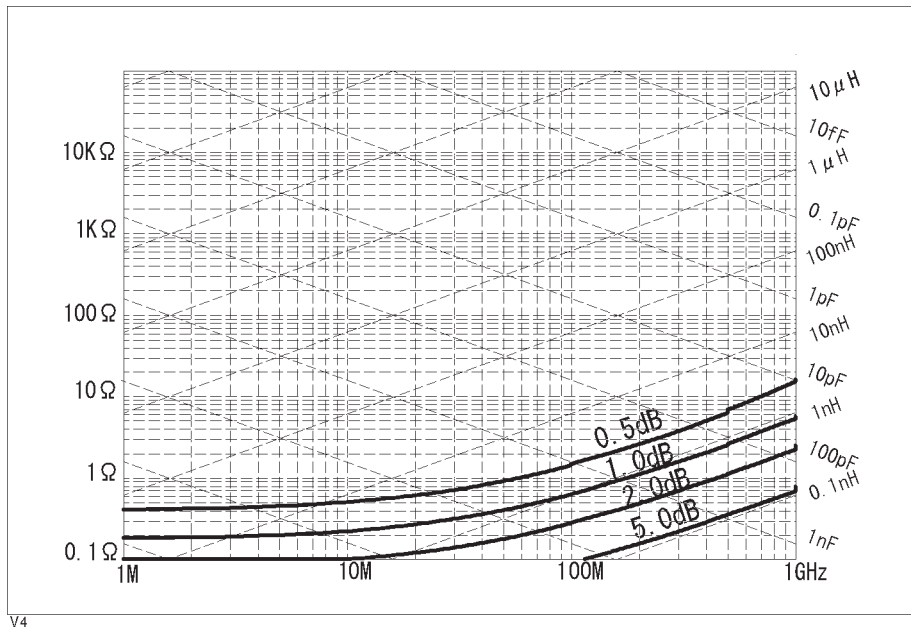


Figure 1. Typical Voltage Level Monitor Accuracy (@N_{av} = 8, V_{osc} = 0.2 V)

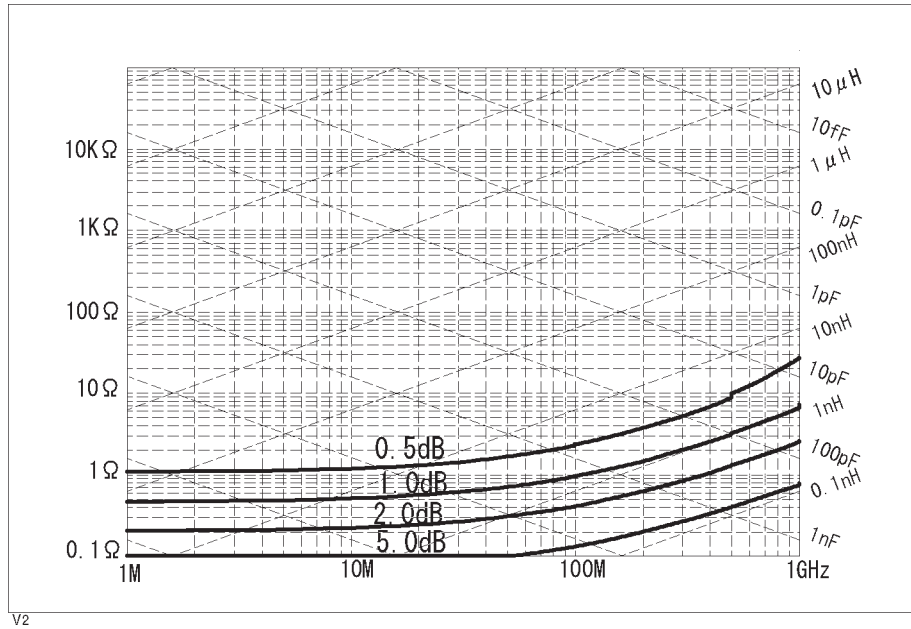


Figure 2. Typical Voltage Level Monitor Accuracy (@ $N_{av} = 1$, $V_{osc} = 0.2$ V)

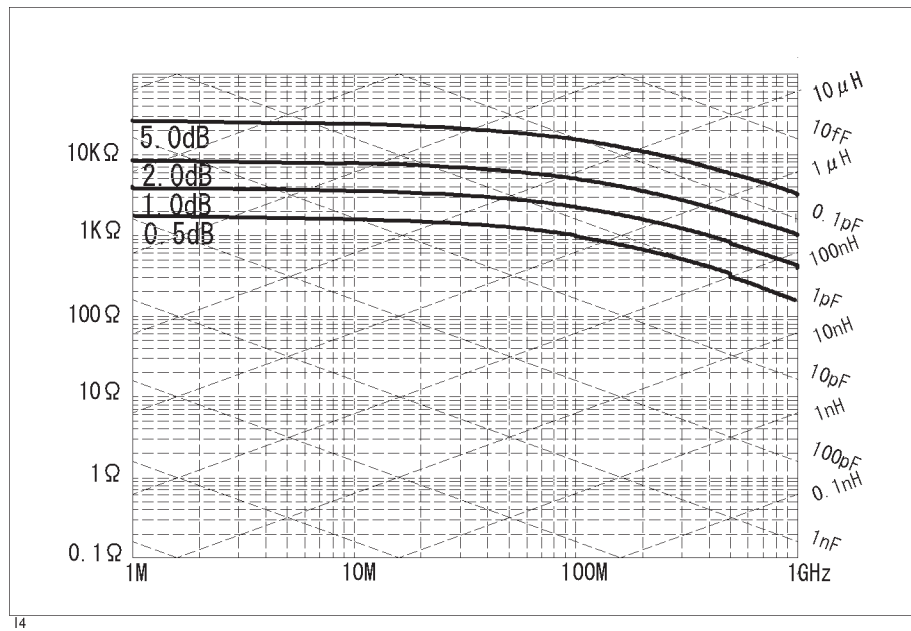
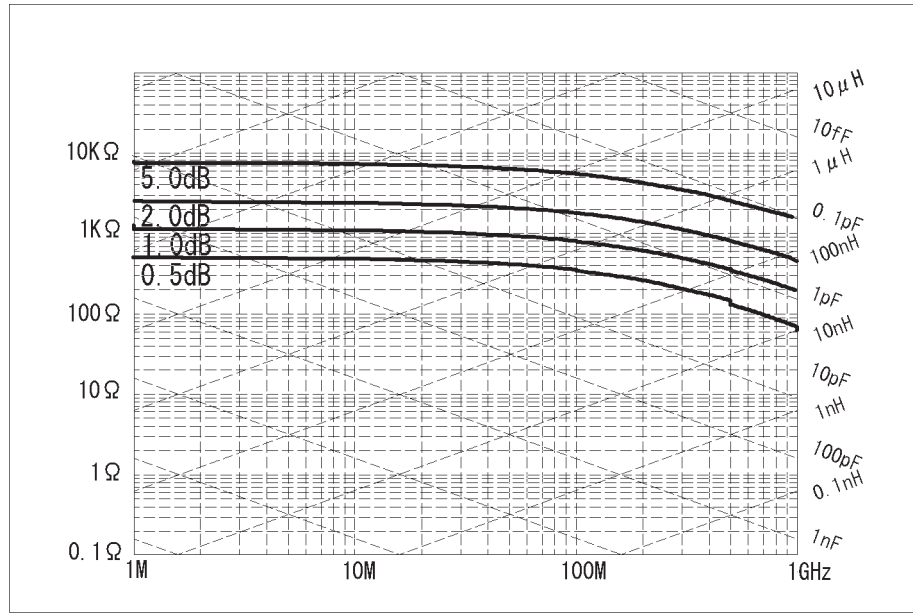


Figure 3. Typical Current Level Monitor Accuracy (@ $N_{av} = 8$, $V_{osc} = 0.2$ V)



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Figure 4. Typical Current Level Monitor Accuracy (@ $N_{av} = 1$, $V_{osc} = 0.2$ V)

Measurement Function

Measurement Parameters

..... L_p -D, L_p -Q, L_p -G, L_p -R_p, L_s -D, L_s -Q, L_s -R_s, R-X, $|Z|$ - θ_{rad} , $|Z|$ - θ_{deg} ,
 C_p -D, C_p -Q, C_p -G, C_p -R_p, C_s -D, C_s -Q, C_s -R_s, G-B, $|Y|$ - θ_{rad} , $|Y|$ - θ_{deg}

Measurement Range

Impedance

@ 1MHz, accuracy < 10%, $N_{av} \geq 8$, $V_{osc} \geq 0.2$ V 200 m Ω to 3 k Ω

Inductance

@ Q < 100, depends on frequency 1 nH to 100 μ H

Contact Check Function

Measurement Current < 1 mA

List Sweep Characteristics

Sweep Mode Continuous, Single, Manual

Sweep Direction Up sweep

Number of Measurement Point 1 to 10 points

Averaging Point average

Delay Time Point delay time, Sweep delay time

Calibration / Compensation Function

Calibration Function Open/Short/50 Ω calibration, Low loss calibration

Compensation Function Open/Short/Load compensation, Port extension, Electric length

Calibration Measurement Points

Fixed Cal

This calibration measures the following FIXED points :

1.0	1.03	1.06	1.09	1.12	1.15	1.18	1.21	1.24	1.26
1.29	1.32	1.35	1.38	1.41	1.44	1.47	1.5	1.55	1.6
1.65	1.7	1.75	1.8	1.85	1.9	1.95	2.0	2.1	2.2
2.3	2.4	2.5	2.6	2.8	3.0	3.2	3.4	3.6	3.8
4.0	4.2	4.4	4.6	4.8	5.0	5.5	6.0	6.5	7.0
7.5	8.0	9.0	10	10	12	13	14	15	16
18	20	22	24	26	28	30	33	36	39
42	45	48	51	55	60	65	70	75	80
85	90	95	100	100	120	130	140	150	160
170	180	190	200	210	220	230	240	250	260
270	280	290	300	310	320	330	340	350	360
370	380	390	400	410	420	430	440	450	460
470	480	490	500	510	520	530	540	550	560
570	580	590	600	610	620	630	640	650	660
670	680	690	700	710	720	730	740	750	760
770	780	790	800	810	820	830	840	850	860
870	880	890	900	910	920	930	940	950	960
970	980	990	1000						

(UNIT:MHz)

User Cal

SPACEFILL This calibration measures the frequency points that are defined by the list sweep table.

Measurement Accuracy

Conditions of accuracy specifications

- Open/Short/50 Ω calibration must be done. Calibration ON.
- Averaging (on point) factor is larger than 32 at which calibration is done if Cal points is set to USER DEF.
- Measurement points are same as the calibration points.
- Environment temperature is within ±5°C of temperature at which calibration is done, and within 13°C to 33°C. Beyond this environmental temperature condition, accuracy is twice as bad as specified.
- 7 mm connector is used.
- When the analyzer frequency is identical to the transmitted interference signal frequency, refer to "EMC" in "General Characteristics".

Contact Check Measurement Accuracy

@ measurement range : 0.1 Ω to 100 Ω, resolution : 1 mΩ ± {3 + (25mΩ/R_{dut} + R_{dut}/10kΩ) × 100} [%]

|Z|, |Y| Accuracy ±(E_a + E_b) [%]

θ Accuracy ± $\frac{(E_a + E_b)}{100}$ [rad]

L, C, X, B Accuracy ±(E_a + E_b) × $\sqrt{(1 + D_x^2)}$ [%]

R, G Accuracy ±(E_a + E_b) × $\sqrt{(1 + Q_x^2)}$ [%]

D Accuracy (ΔD)

@|D_x tan $\frac{(E_a + E_b)}{100}$ | < 1 ± $\frac{(1 + D_x^2) \tan(\frac{E_a + E_b}{100})}{1 \mu D_x \tan(\frac{E_a + E_b}{100})}$

Especially, @ D_x ≤ 0.1 ± $\frac{(E_a + E_b)}{100}$

Q Accuracy (ΔQ)

@|Q_x tan $\frac{(E_a + E_b)}{100}$ | < 1 ± $\frac{(1 + Q_x^2) \tan(\frac{E_a + E_b}{100})}{1 \mu Q_x \tan(\frac{E_a + E_b}{100})}$

Especially, @ $\frac{10}{(E_a + E_b)} \geq Q_x \geq 10$ ± $Q_x^2 \frac{(E_a + E_b)}{100}$

Where,

E_a : depends on measurement frequency as follows:

1 MHz ≤ Frequency ≤ 100 MHz 0.65 + $\frac{0.03}{V_{osc}}$ [%]

100 MHz < Frequency ≤ 500 MHz 0.8 + $\frac{0.03}{V_{osc}}$ [%]

500 MHz < Frequency ≤ 1000 MHz 1.2 + $\frac{0.03}{V_{osc}}$ [%]

E_b : (Z_s/|Z_x| + Y₀/|Z_x|) × 100 [%]

V_{osc} : OSC level [V]

Z_x : impedance measurement value [Ω]

Z_s and Y₀ depend on number of point averaging (N_{av}) and OSC level (V_{osc}) as follows:

Measurement Conditions		Z_s [m Ω]	Y_o [μ S]
Number of Point Averaging (N_{av})	OSC Signal Level (V_{osc})		
$1 \leq N_{av} \leq 7$	$0.2 \text{ V} \leq V_{osc} \leq 1 \text{ V}$	$50 + 1 \times f_{\text{[MHz]}}$	$100 + 0.4 \times f_{\text{[MHz]}}$
	$0.01 \text{ V} \leq V_{osc} < 0.2 \text{ V}$	$\frac{0.2}{V_{osc}} \times (50 + 1 \times f_{\text{[MHz]}})$	$\frac{0.2}{V_{osc}} \times (100 + 0.4 \times f_{\text{[MHz]}})$
$N_{av} \geq 8$	$0.2 \text{ V} \leq V_{osc} \leq 1 \text{ V}$	$20 + 0.5 \times f_{\text{[MHz]}}$	$30 + 0.2 \times f_{\text{[MHz]}}$
	$0.01 \text{ V} \leq V_{osc} < 0.2 \text{ V}$	$\frac{0.2}{V_{osc}} \times (20 + 0.5 \times f_{\text{[MHz]}})$	$\frac{0.2}{V_{osc}} \times (30 + 0.2 \times f_{\text{[MHz]}})$

At the following frequency points, instrument spurious characteristics could occasionally cause measurement errors to exceed specified value because of instrument spurious characteristics.

10.71 MHz 17.24 MHz 21.42 MHz 42.84 MHz
 514.65 MHz 686.19 MHz

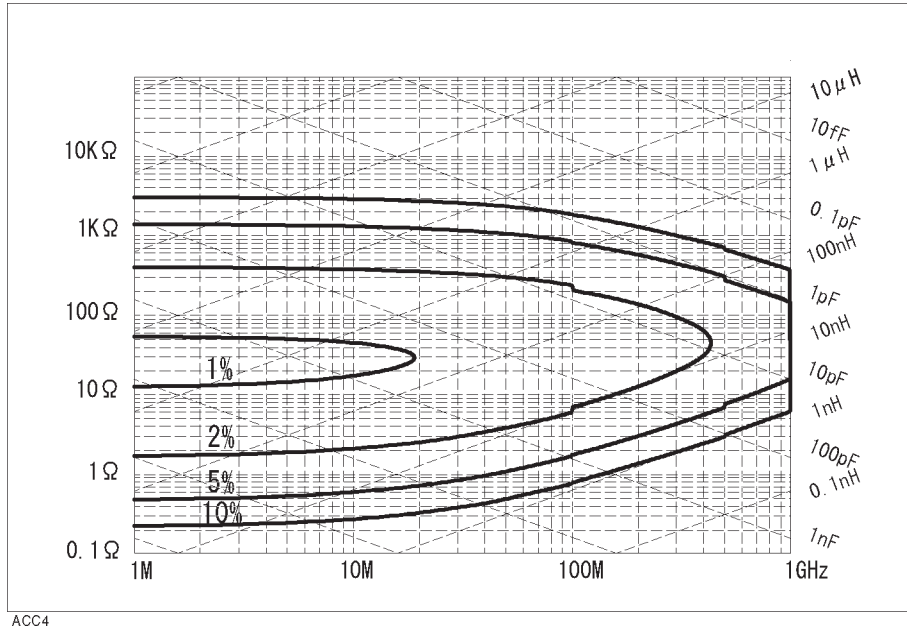


Figure 5. Measurement Accuracy (@ $N_{av} = 8$, $V_{osc} = 0.2$ V)

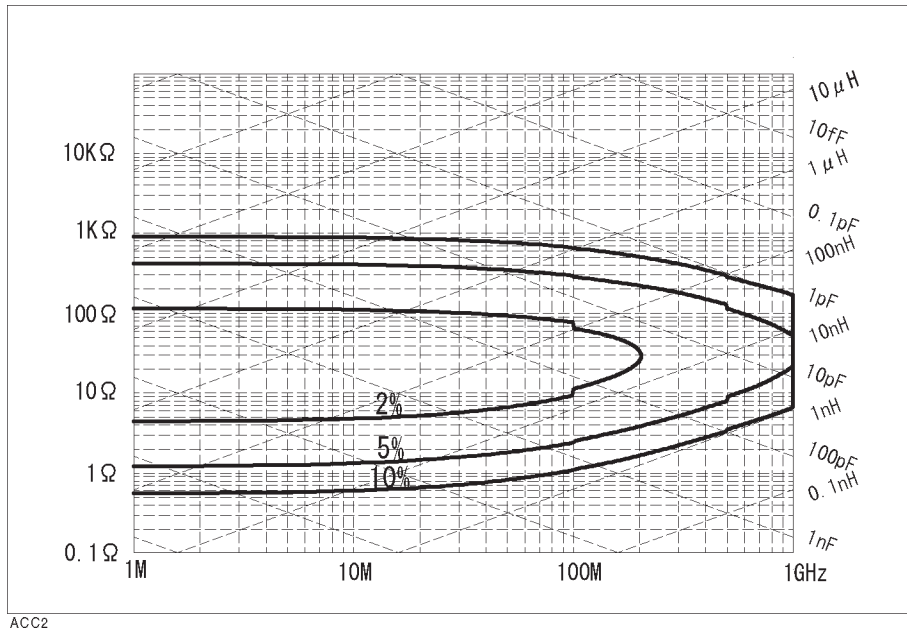


Figure 6. Measurement Accuracy (@ $N_{av} = 1$, $V_{osc} = 0.2$ V)

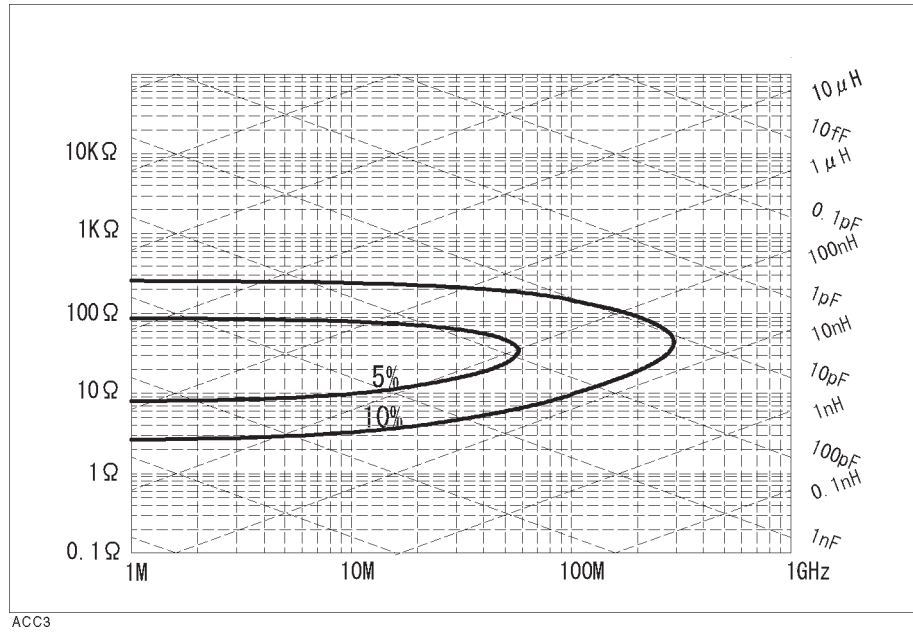


Figure 7. Measurement Accuracy (@ $N_{av} = 8$, $V_{osc} = 0.02$ V)

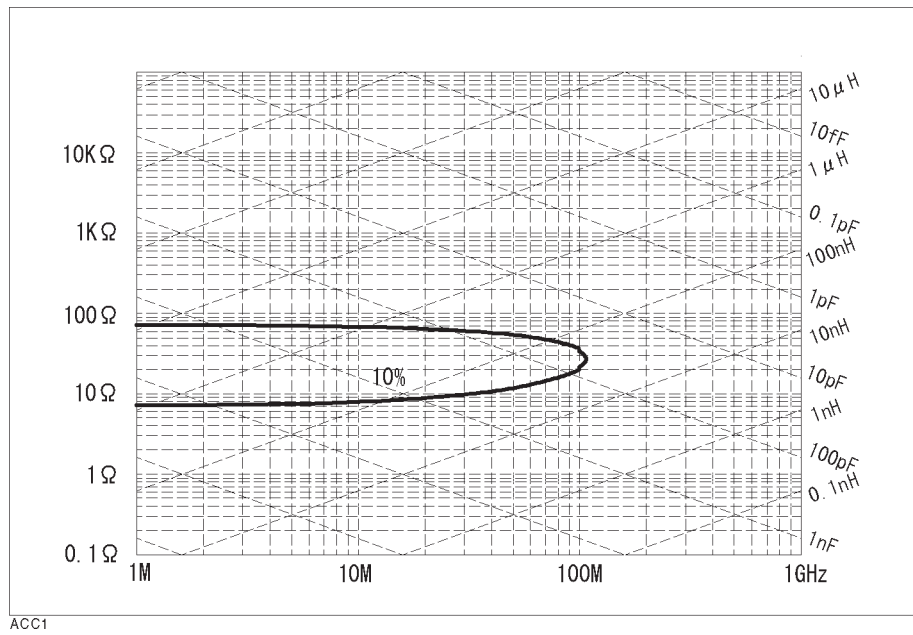


Figure 8. Measurement Accuracy (@ $N_{av} = 1$, $V_{osc} = 0.02$ V)

Typical Measurement Accuracy

Conditions of typical accuracy specifications

- Open/Short/50 Ω calibration must be done. Calibration ON.
- Averaging (on point) factor is larger than 32 at which calibration is done if Cal points is set to USER DEF.
- Measurement points are same as the calibration points.
- Environment temperature is within ±5°C of temperature at which calibration is done, and within 13°C to 33°C. Beyond this environmental temperature condition, accuracy is twice as bad as specified.
- 7 mm connector is used.

$$|Z|, |Y| \text{ Accuracy} \dots\dots\dots \pm(E_a + E_b) \text{ [%]}$$

$$\theta \text{ Accuracy} \dots\dots\dots \pm \frac{(E_a + E_b)}{100} \text{ [rad]}$$

$$\mathbf{L, C, X, B Accuracy} \dots\dots\dots \pm(E_a + E_b) \times \sqrt{(1 + D_x^2)} \text{ [%]}$$

$$\mathbf{R, G Accuracy} \dots\dots\dots \pm(E_a + E_b) \times \sqrt{(1 + Q_x^2)} \text{ [%]}$$

D Accuracy (ΔD)

$$\text{@ } |D_x \tan \frac{(E_a + E_b)}{100}| < 1 \dots\dots\dots \pm \frac{(1 + D_x^2) \tan(\frac{E_a + E_b}{100})}{1 \mu D_x \tan(\frac{E_a + E_b}{100})}$$

$$\text{Especially, @ } D_x \leq 0.1 \dots\dots\dots \pm \frac{(E_a + E_b)}{100}$$

Q Accuracy (ΔQ)

$$\text{@ } |Q_x \tan \frac{(E_a + E_b)}{100}| < 1 \dots\dots\dots \pm \frac{(1 + Q_x^2) \tan(\frac{E_a + E_b}{100})}{1 \mu Q_x \tan(\frac{E_a + E_b}{100})}$$

$$\text{Especially, @ } \frac{10}{(E_a + E_b)} \geq Q_x \geq 10 \dots\dots\dots \pm Q_x^2 \frac{(E_a + E_b)}{100}$$

Where,

E_a : depends on measurement frequency as follows:

1 MHz ≤ Frequency ≤ 100 MHz	0.56 + 0.03 $\frac{0.03}{V_{osc}}$ [%] (Typical)
100 MHz < Frequency ≤ 500 MHz	0.63 + 0.03 $\frac{0.03}{V_{osc}}$ [%] (Typical)
500 MHz < Frequency ≤ 1000 MHz	0.70 + 0.03 $\frac{0.03}{V_{osc}}$ [%] (Typical)

E_b : (Z_s/|Z_x| + Y₀/|Z_x|) × 100 [%]

V_{osc} : OSC level [V]

Z_x : impedance measurement value [Ω]

Z_s and **Y₀** depend on number of point averaging (N_{av}) and OSC level (V_{osc}) as follows:

Measurement Conditions		Z _s [mΩ]	Y ₀ [μS]
Number of Point Averaging (N _{av})	OSC Signal Level (V _{osc})	(Typical)	(Typical)
1 ≤ N _{av} ≤ 7	0.2 V ≤ V _{osc} ≤ 1 V	20 + 0.05 × f _[MHz]	7 + 0.1 × f _[MHz]
	0.01 V ≤ V _{osc} < 0.2 V	$\frac{0.2}{V_{osc}} \times (20 + 0.05 \times f_{[MHz]})$	$\frac{0.2}{V_{osc}} \times (7 + 0.1 \times f_{[MHz]})$
N _{av} ≥ 8	0.2 V ≤ V _{osc} ≤ 1 V	7 + 0.05 × f _[MHz]	5 + 0.1 × f _[MHz]
	0.01 V ≤ V _{osc} < 0.2 V	$\frac{0.2}{V_{osc}} \times (7 + 0.05 \times f_{[MHz]})$	$\frac{0.2}{V_{osc}} \times (5 + 0.1 \times f_{[MHz]})$

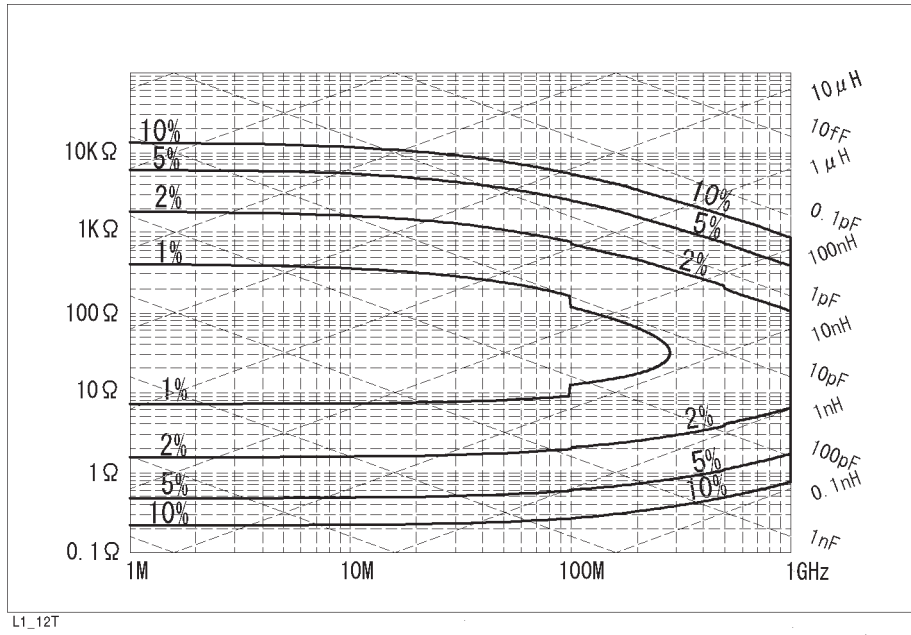


Figure 9. Typical Measurement Accuracy (@ $N_{av} = 1$, $V_{osc} = 0.2$ V)

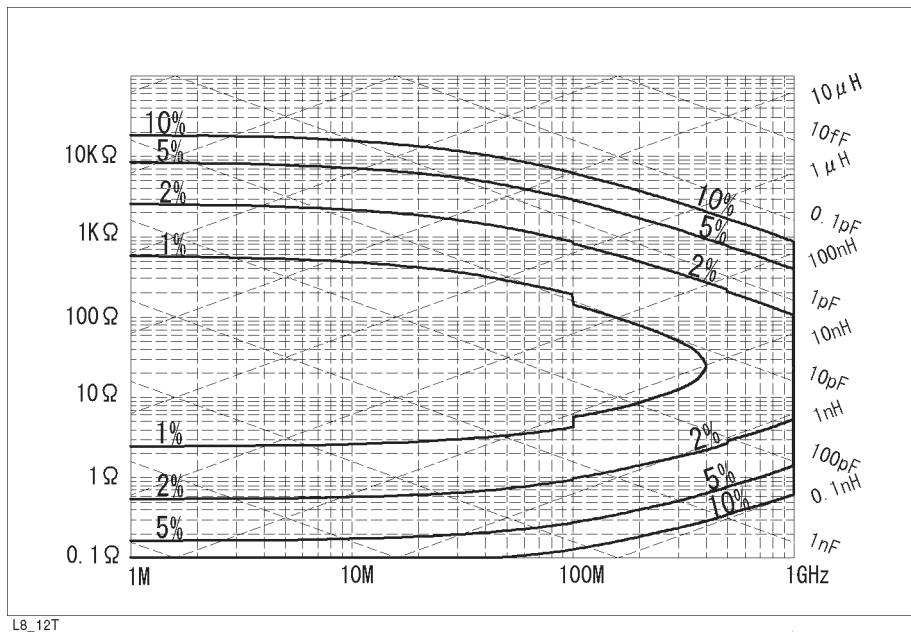


Figure 10. Typical Measurement Accuracy (@ $N_{av} = 8$, $V_{osc} = 0.2$ V)

Typical measurement accuracy when open/short/50 Ω/low-loss-capacitor calibration is done

Conditions

- Averaging on point factor is larger than 32 at which calibration is done.
- Cal Points is set to USER DEF.
- Environment temperature is within ±5 °C of temperature at which calibration is done, and within 13 °C to 33 °C. Beyond this environmental temperature condition, accuracy is twice as bad as specified.
- 7 mm connector is used.

|Z|, |Y| Accuracy ±(E_a + E_b) [%]

θ Accuracy ± $\frac{E_c}{100}$ [rad]

L, C, X, B Accuracy ± $\sqrt{(E_a + E_b)^2 + (E_c D_x)^2}$ [%]

R, G Accuracy ± $\sqrt{(E_a + E_b)^2 + (E_c Q_x)^2}$ [%]

D Accuracy

@ |D_x tan (E_c/100)| < 1 ± $\frac{(1 + D_x^2) \tan(E_c/100)}{1 \mu D_x \tan(E_c/100)}$

Especially, D_x ≤ 0.1 ± $\frac{E_c}{100}$

Q Accuracy

@ Q_x tan (E_c/100) ± $\frac{(1 + Q_x^2) \tan(E_c/100)}{1 \mu Q_x \tan(E_c/100)}$

Especially, $\frac{10}{E_c} \geq Q_x \geq 10$ ± $Q_x^2 \frac{E_c}{100}$

Where,

D_x : Actual D value of DUT

E_a, E_b : are as same as E_a and E_b of the measurement accuracy when OPEN/SHORT/50 Ω calibration is done.

E_c = 0.06 + 0.08 × $\frac{F}{1000}$ (Typical)

F : measurement frequency [MHz]

Q_x : Actual Q value of DUT

Trigger Function

Trigger Source Internal, Manual, External, Bus

Throughput

For a time from triggering to EOM ≤ 15 msec/point

Display

Type/Size Monochrome CRT. 7 inch, Text screen only

Resolution 512 dots \times 304 lines

Data Storage

Type Built-in flexible disk drive, Battery backup SRAM disk memory

Capacity

Built-in flexible disk 720 kB/1.44 MB

Battery backup SRAM disk memory 256 kB

Operating time of battery backup SRAM disk memory 3 days

Disk format LIF, DOS

Interface

HP-IB

Interface IEEE 488.1-1987, IEC625,
JIS C 1901-1987 standard compatible.

Interface function SH1, AH1, T6, TE0, L4, LE0, SR1, RL1,
PPO, DC1, DT1, C1, C2, C3, C4, C11, E2

Numeric Data Transfer formats ASCII
32 and 64 bit IEEE 754 Floating point format,
DOS PC format (32 bit IEEE with byte order reversed)

Protocol IEEE 488.2-1987

Handler Interface

Interface All output signals are negative logic, opto-isolated open collector outputs.

Output Signals Sort Judgments (BIN1 to BIN9, AUX_BIN, OUT_OF_BIN, PHI, PLO, SREJ),
Contact Check (NO_CONTACT), /FAIL, End Of Analog Processing
(INDEX) , End-Of-Measurement (EOM), Power Line Fail (ALARM)

Input Signals External trigger (EXT_TRIG), Front panel key lock (KEY_LOCK)

Input Output Characteristics

External reference input

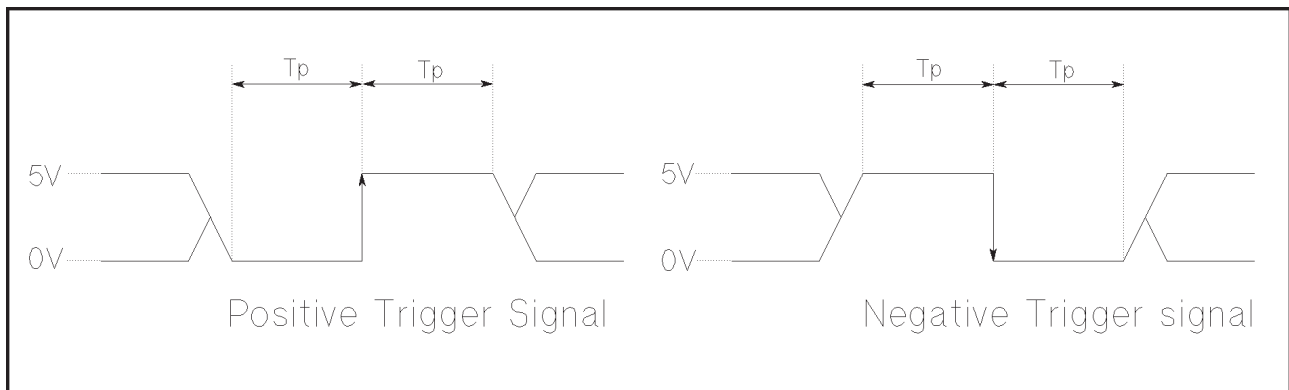
Frequency	10 MHz±100 Hz (typically)
Level	> -6 dBm (typically)
Input impedance	50 Ω (nominal)
Connector	BNC female

Internal Reference Output

Frequency	10 MHz (nominal)
Level	2 dBm (typically)
Output Impedance	50 Ω (nominal)
Connector	BNC female

External trigger input

Level	TTL Level
Pulse width (T_p)	> 2 μs (typically)
Polarity	positive/negative selective
Connector	BNC female



CG600010

Figure 11. Trigger Signal

General Characteristics

Operation Conditions

Temperature

Disk drive non-operating condition	0°C to 55°C
Disk drive operating condition	10°C to 50°C

Humidity

@wet bulb temperature <29°C, without condensation

Disk drive non-operating condition	15 % to 95 % RH
Disk drive operating condition	15 % to 80 % RH

Altitude

0 to 2,000 meters

Warm up time

30 minutes

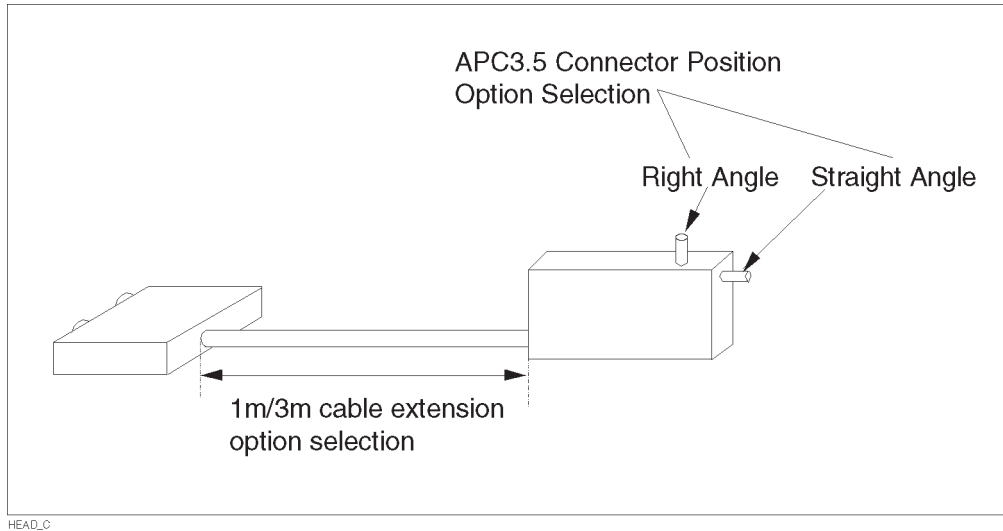
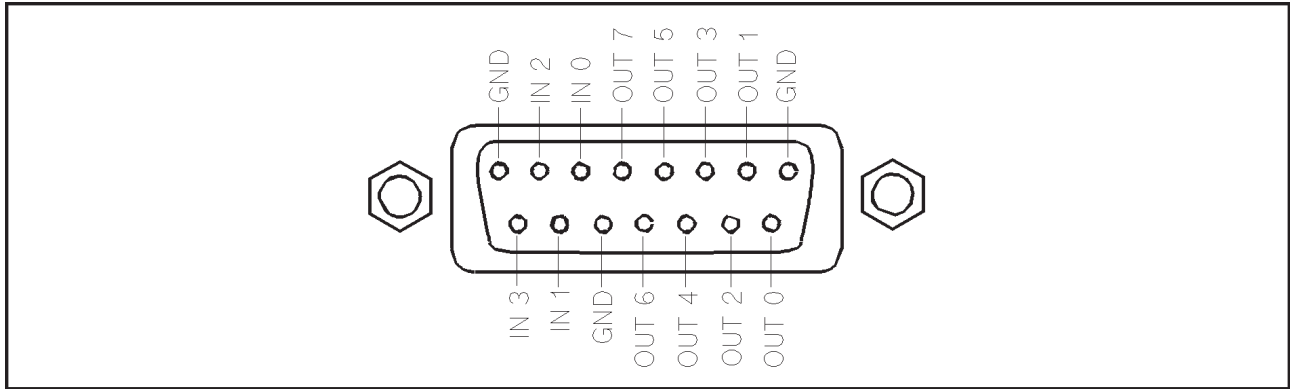


Figure 13. Dimensions of Test Heads (2/2)

Specification for Option 1C2 HP Instrument BASIC

External program Run/Cont input

Connector	BNC female
Level	TTL
Keyboard connector	HP-HIL
I/O port	4 bit in/ 8 bit out port, TTL Level



C660001

Figure 14. I/O Port Pin Assignment

I/O port pin assignments

Specification for Option 004 Working Standard

Supplied shorting device size

P/N 16191-29005	1.0 × 0.5 mm
P/N 16191-29006	1.6 × 0.8 mm
P/N 16191-29007	2.0 × 1.25 mm
P/N 16191-29008	3.2 × 1.6 mm

Supplied resistor size

P/N 5182-0433	1.0 × 0.5 mm
P/N 5182-0434	1.6 × 0.8 mm
P/N 5182-0435	2.0 × 1.25 mm
P/N 5182-0436	3.2 × 1.6 mm

DC resistance of supplied chip resistor 51Ω ±0.5 %

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